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# Characterization of Two Dimensional Materials and Fabrication of the Transistor and Heterostructure



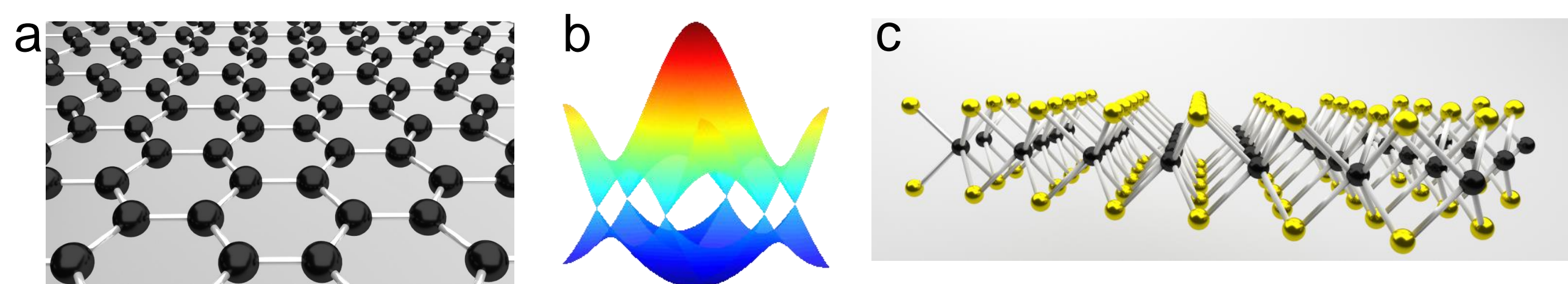
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## Introduction

Two-dimensional (2D) material is a material in which the atomic organization and bond strength along two-dimensions are similar and much stronger than along a third dimension. 2D material such as graphene, boron nitride (BN), and transition metal dichalcogenides (TMDCs) have unique electrical, optical, and mechanical properties that can be used in a wide range of applications.<sup>1</sup> By vertically stacking different 2D semiconducting crystals on top of each other with van-der-Waals forces, Van der Waals heterostructures are expected to show combined functionality of the individual layers, and also new phenomena resulting from the interface.<sup>2</sup> Here, single/few layers graphene and molybdenum disulfide (MoS<sub>2</sub>) obtained and studied by Mechanical Cleavage and Raman spectrum. Further transfer process and electrodes fabrication are conducted to build 2D materials based transistors/heterostructures.



**Figure 1.** lattice structure of (a) graphene and (b) single layer MoS<sub>2</sub>. (b) Band structure of Graphene.

As Figure 1 shows, Graphene is a single layer of carbon packed in a hexagonal lattice (honeycomb), with a covalent bond distance of 0.142 nm. Graphene is a zero-gap semiconductor since its conduction and valence bands meet at the Dirac points.

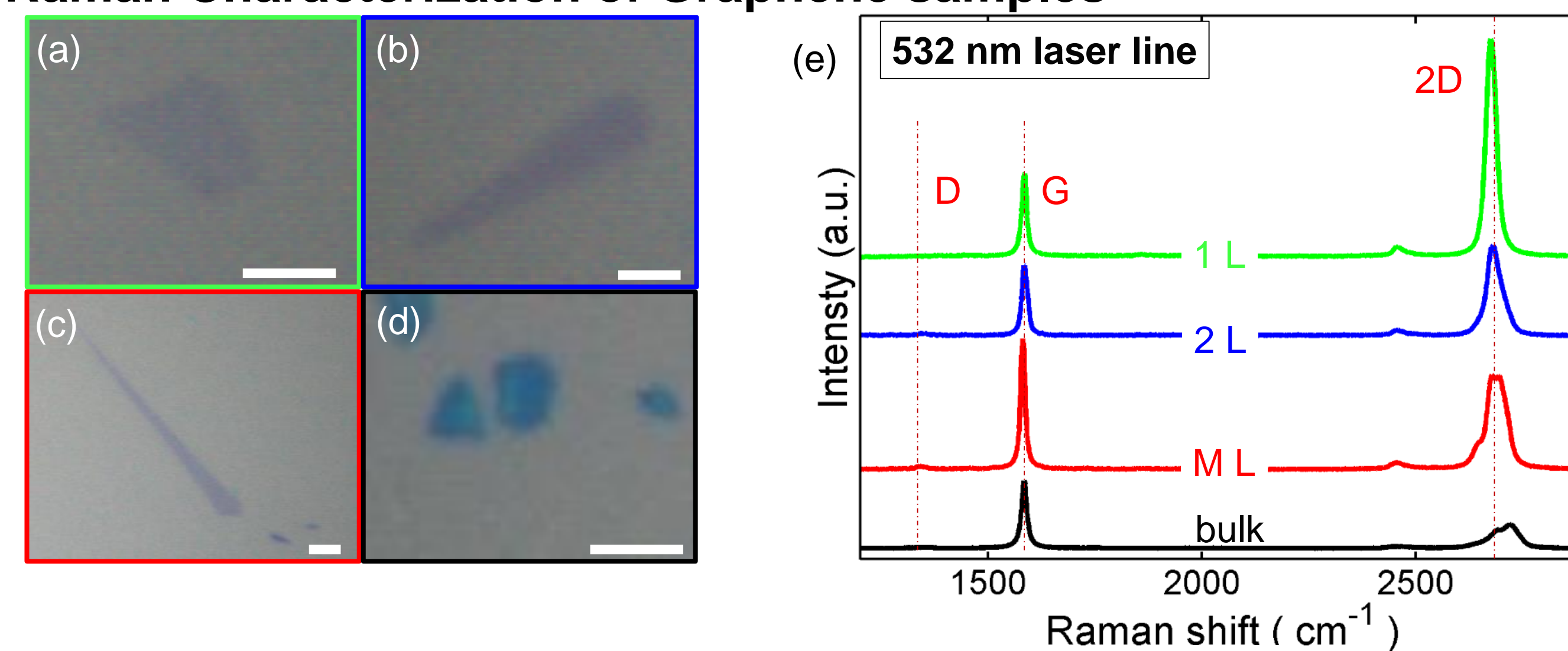
In each MoS<sub>2</sub> layer, hexagonally packed molybdenum atoms are between two layers of sulfide atoms. Bulk MoS<sub>2</sub> is semiconducting with an indirect bandgap of 1.2 eV, whereas single-layer MoS<sub>2</sub> is a direct gap semiconductor with a bandgap of 1.8 eV.

## Method

- **Mechanical Cleavage:** The primary and most effective way comparing with other method, which provide graphene with the highest quality.
- **Raman microscope:** Raman spectra are studied to characterize materials and identify single/few layers from their bulk material.
- PDMS based transfer technique for 2D material.
- Electron Beam Lithography and Thermal Evaporation for electrodes fabrication.

## Results and discussion

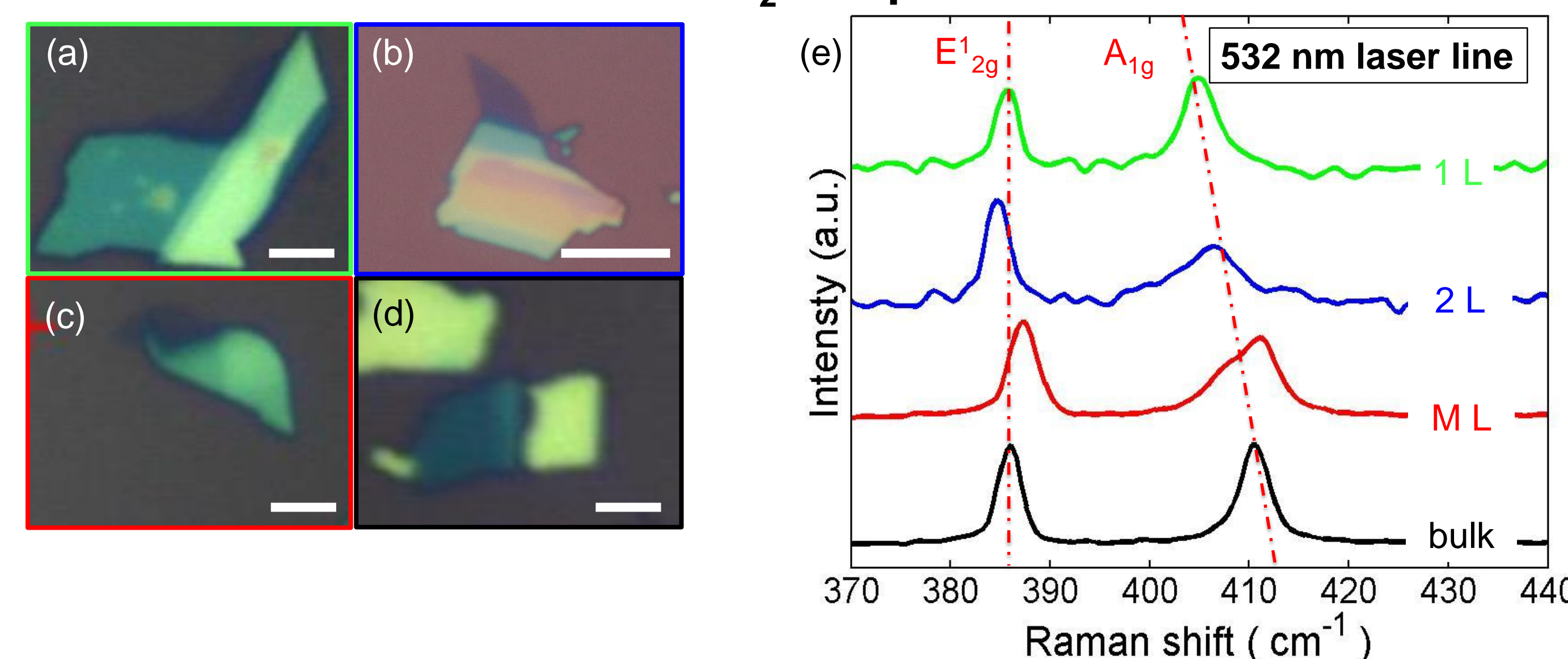
### ➤ Raman Characterization of Graphene samples



**Figure 2.** a-d are four graphite samples with different layer numbers. (a) length is 4.62  $\mu\text{m}$  and ROI is 21/8. (b) Length 7  $\mu\text{m}$  and ROI is 17/13. (c) Length 21.17  $\mu\text{m}$  and ROI is 17/24. (d) Length 5.32  $\mu\text{m}$  and ROI is 1/3. (e) Raman characterization of sample a-d using 532 laser line. The spectra are offset vertically for clarity. The scale bars are 5  $\mu\text{m}$ .

Graphene can be identified by the position and shape of its peak G (1580  $\text{cm}^{-1}$ ) and peak 2D (2690  $\text{cm}^{-1}$ ). The first-order D peak itself is not visible in pristine graphene because of crystal symmetries. While the number of the graphite layers decreases, the ratio of intensity,  $I_{2D}/I_G$ , increases.

### ➤ Raman Characterization of MoS<sub>2</sub> samples

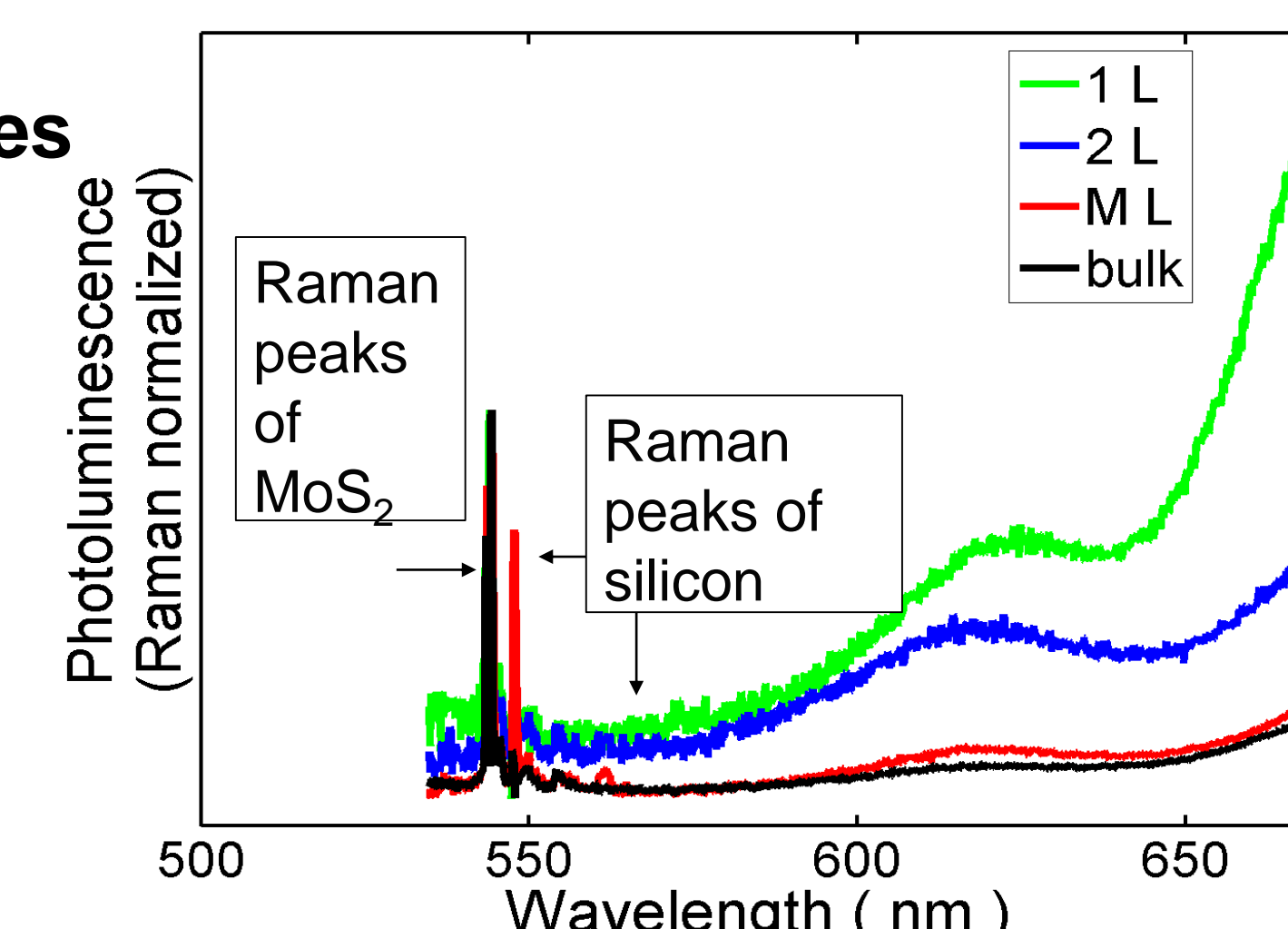


**Figure 3.** a-d are four MoS<sub>2</sub> samples with different layer numbers. (e) Raman characterization of sample a-d using 532 laser line. The spectra are offset vertically for clarity. The scale bars are 5  $\mu\text{m}$ .

$E_{12g}$  ( $\sim 385 \text{ cm}^{-1}$  for bulk MoS<sub>2</sub>) and  $A_{1g}$  ( $\sim 411 \text{ cm}^{-1}$  for bulk MoS<sub>2</sub>) modes are observed in both monolayer and bulk MoS<sub>2</sub>. However, it is found that the intensity of  $E_{12g}$  peak decreases while that of the  $A_{1g}$  peak increases with increasing layer number. Additionally, the distance of these two peaks increase from 19.08 - 24.45  $\text{cm}^{-1}$ .

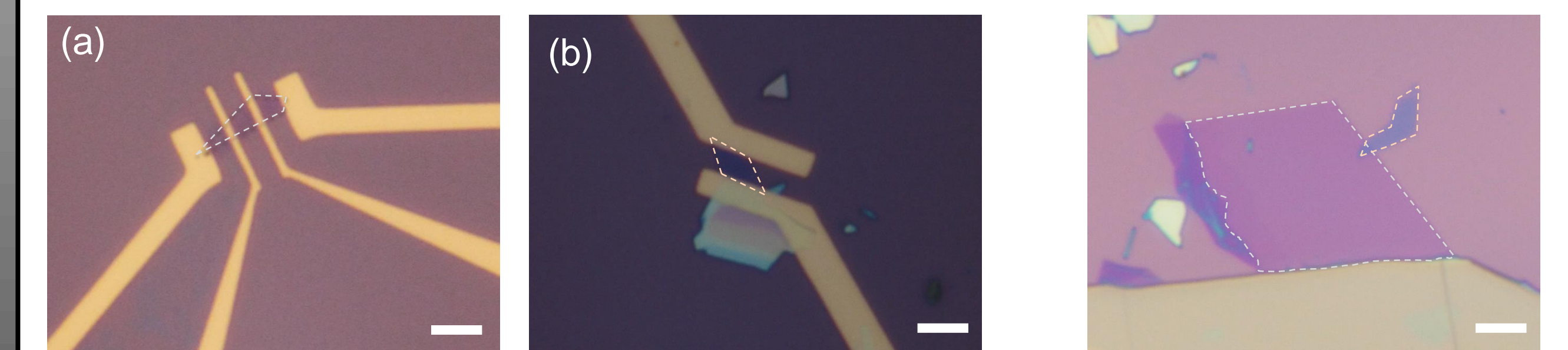
### ➤ Photoluminescence of MoS<sub>2</sub> samples

Single layer MoS<sub>2</sub> exhibits significantly stronger photoluminescence (PL)  $\sim 675\text{nm}$  than bilayer MoS<sub>2</sub>. The different PL spectra also indicates that a monolayer MoS<sub>2</sub> is a direct bandgap material while a multilayer MoS<sub>2</sub> is an indirect material.<sup>3,4</sup>



**Figure 3.** raman intensity normalized photoluminescence of sample (a)-(d) excited by 532nm laser.

### ➤ Fabrication of Graphene and MoS<sub>2</sub> transistor



**Figure 3.** a and b are Graphene and MoS<sub>2</sub> transistors. (c) is Graphene/MoS<sub>2</sub> heterostructure. Graphene and MoS<sub>2</sub> pieces are outlined by light gray and orange color dashed lines. The scale bars are 5  $\mu\text{m}$ .

### ➤ Graphene/MoS<sub>2</sub> heterostructure

Graphene piece are carefully cleaved from their bulk material onto thin Polydimethylsiloxane (PDMS) stamp. Then, a micro-manipulator is used to place the graphene layer on the top of prepared MoS<sub>2</sub> layer through an aligned transfer procedure.<sup>5</sup>

## Conclusion

- Through Mechanical Cleavage, graphene and monolayer MoS<sub>2</sub> are successfully obtained from their bulk material. Studying Raman characteristics, we can distinguish unique properties. Transferring 2D material can be done using PDMA, to fabricate transistors and other optical electronics.
- **Future Work:** Fabricating single layer MoS<sub>2</sub> and WSe<sub>2</sub>. Creating a N doped and P doped heterojunction for dye sensitized solar cells.

## Reference

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